Search Notes



Class

Appl	icati	ion/	Con	trol	No.	

10082794

Applicant(s)/Patent Under Reexamination

BAU ET AL.

Examiner Rutten, J. Derek Art Unit

CEADCHED

SEARCHED		
Subclass	Date	Examiner

SEARCH NOTES						
Search Notes	Date	Examiner				
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	2/8/07	/jdr/				
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	6/4/08	/jdr/				
ACM - portal.acm.org - see search history printout	6/4/08	/jdr/				
Tuan Dam (consulted re. allowable subj. matter)	6/4/08	/jdr/				
IEEE (leeexplore.leee.org), Google (www.google.com) - see search history printout						
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	6/5/08	/jdr/				

INTERFERENCE SEARCH						
Class	Subclass	Date	Examiner			
717	109,113,117,143					
719	313,330	6/5/08	/jdr/			